You are to design a test to get as close as possible to 100% fault coverage for the following circuit.

1. Considering all stuck-at faults in this circuit, collapse the fault set by finding equivalent and dominating faults, and list a minimal set of faults that should be tested. Detection of the faults in this collapsed set should ensure detection of any faults in the circuit.

2. Use the D algorithm, or any other method, to derive a set of test vectors that will detect the faults in your collapsed fault set. If a fault is determined to be untestable, indicate how you determined that.

3. Use the fault simulation capability of FastScan to verify that your set of test vectors detects all of the faults in the circuit.

4. Use the ATPG capability of FastScan to generate a test for the above circuit, and compare the generated test set to the one you created manually. Specifically, point out how many test vectors FastScan generated and the fault coverage of that test set.

NOTE: FastScan requires a VHDL or Verilog netlist of the circuit. You should create this netlist by instantiating gates from the ADK library.